

Docket No.: 057810-0088



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 20277
Eiji MARUYAMA	:	Confirmation Number: 2908
Application No.: 10/790,759	:	Group Art Unit: 1709
Filed: March 03, 2004	:	Examiner: Not Yet Assigned
For: PHOTOVOLTAIC DEVICE AND DEVICE HAVING TRANSPARENT CONDUCTIVE FILM		

INFORMATION DISCLOSURE STATEMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed more than three months after the U.S. filing date AND after the mailing date of the first Office Action on the merits, but before the mailing date of a Final Rejection or Notice of Allowance.

CERTIFICATION PARAGRAPH

The undersigned certifies that each item of information contained in this Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement as described in 37 CFR 1.97(e)(1).

Each reference was cited in a corresponding foreign application search report and its relevance is discussed therein. A copy of the foreign search report is attached for the Examiner's information.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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**Please recognize our Customer No. 20277
as our correspondence address.**



SHEET 1 OF 1

INFORMATION DISCLOSURE
CITATION IN AN
APPLICATIONATTY. DOCKET NO.
057810-0088SERIAL NO.
10/790,759APPLICANT
Eiji MARUYAMA

(PTO-1449)

FILING DATE
March 03, 2004GROUP
1709

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number 4 - Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
		EP 1 187 223 A2	03-13-2002	SANYO ELECTRIC CO., LTD		X	
		EP 0 892 590 A2	01-20-1999	TDK CORPORATION		X	
		EP 0 461 908 A2	12-18-1991	FUJITSU LIMITED		X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		NEERINCK, D.G., et al., "Depth profiling of thin ITO films by grazing incidence X-ray diffraction", THIN SOLID FILMS, May 15, 1996, Pages 12-17, Elsevier Science S.A.
		JOSHI, R.N., et al., "Characteristics of indium tin oxide films deposited by r.f. magnetron sputtering", THIN SOLID FILMS, February 15, 1995, Pages 32-35, Elsevier Science S.A.
		THILAKAN, P., et al., "Oxidation dependent crystallization behaviour of IO and ITO thin films deposited by reactive thermal deposition technique", MATERIAL SCIENCE & ENGINEERING B, 1998, Pages 195-200, Elsevier Science S.A.
		European Search Report issued in corresponding European Patent Application No. EP 04 25 1457, dated April 13, 2007

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.